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Details

Product Status	Active
Number of LABs/CLBs	37200
Number of Logic Elements/Cells	476160
Total RAM Bits	39223296
Number of I/O	840
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 100°C (TJ)
Package / Case	1759-BBGA, FCBGA
Supplier Device Package	1759-FCBGA (42.5x42.5)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6vsx475t-2ffg1759e

Important Note

Typical values for quiescent supply current are specified at nominal voltage, 85°C junction temperatures (T_j). Xilinx recommends analyzing static power consumption at $T_j = 85^\circ\text{C}$ because the majority of designs operate near the high end of the commercial temperature range. Quiescent supply current is specified by speed grade for Virtex-6 devices. Use the XPower™ Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate static power consumption for conditions other than those specified in Table 4.

Table 4: Typical Quiescent Supply Current

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M) ⁽²⁾	-1L (C)	-1L (I) ⁽¹⁾	
I_{CCINTQ}	Quiescent V_{CCINT} supply current	XC6VLX75T	927	927	927	N/A	656	741	mA
		XC6VLX130T	1563	1563	1563	N/A	1102	1245	mA
		XC6VLX195T	2059	2059	2059	N/A	1441	1628	mA
		XC6VLX240T	2478	2478	2478	N/A	1733	1957	mA
		XC6VLX365T	3001	3001	3001	N/A	2092	2363	mA
		XC6VLX550T ⁽³⁾	N/A	4515	4515	N/A	3147	3555	mA
		XC6VLX760 ⁽³⁾	N/A	5094	5094	N/A	3471	3921	mA
		XC6VSX315T	3476	3476	3476	N/A	2409	2721	mA
		XC6VSX475T ⁽³⁾	N/A	5227	5227	N/A	3622	4091	mA
		XC6VHX250T	2906	2906	2906	N/A	N/A	N/A	mA
		XC6VHX255T	2746	2746	2746	N/A	N/A	N/A	mA
		XC6VHX380T ⁽⁴⁾	4160	4160	4160	N/A	N/A	N/A	mA
		XC6VHX565T ⁽⁵⁾	N/A	5207	5207	N/A	N/A	N/A	mA
		XQ6VLX130T	N/A	1563	N/A	1563	N/A	1245	mA
		XQ6VLX240T	N/A	2478	N/A	2478	N/A	1957	mA
		XQ6VLX550T ⁽⁷⁾	N/A	N/A	N/A	4515	N/A	3555	mA
		XQ6VSX315T	N/A	3476	N/A	3476	N/A	2721	mA
		XQ6VSX475T ⁽⁷⁾	N/A	N/A	N/A	5227	N/A	4091	mA

LVPECL DC Specifications (LVPECL_25)

These values are valid when driving a 100Ω differential load only, i.e., a 100Ω resistor between the two receiver pins. The V_{OH} levels are 200 mV below standard LVPECL levels and are compatible with devices tolerant of lower common-mode ranges. [Table 11](#) summarizes the DC output specifications of LVPECL. For more information on using LVPECL, see [UG361: Virtex-6 FPGA SelectIO Resources User Guide](#).

Table 11: LVPECL DC Specifications

Symbol	DC Parameter	Min	Typ	Max	Units
V_{OH}	Output High Voltage	$V_{CC} - 1.025$	1.545	$V_{CC} - 0.88$	V
V_{OL}	Output Low Voltage	$V_{CC} - 1.81$	0.795	$V_{CC} - 1.62$	V
V_{ICM}	Input Common-Mode Voltage	0.6	—	2.2	V
V_{IDIFF}	Differential Input Voltage ⁽¹⁾⁽²⁾	0.100	—	1.5	V

Notes:

1. Recommended input maximum voltage not to exceed $V_{CCAUX} + 0.2V$.
2. Recommended input minimum voltage not to go below $-0.5V$.

eFUSE Read Endurance

[Table 12](#) lists the maximum number of read cycle operations expected. For more information, see [UG360: Virtex-6 FPGA Configuration User Guide](#).

Table 12: eFUSE Read Endurance

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
DNA_CYCLES	Number of DNA_PORT READ operations or JTAG ISC_DNA read command operations. Unaffected by SHIFT operations.	30,000,000				Read Cycles
AES_CYCLES	Number of JTAG FUSE_KEY or FUSE_CNTL read command operations. Unaffected by SHIFT operations.	30,000,000				Read Cycles

GTX Transceiver Specifications

GTX Transceiver DC Characteristics

Table 13: Absolute Maximum Ratings for GTX Transceivers⁽¹⁾

Symbol	Description	Min	Max	Units
MGTAVCC	Analog supply voltage for the GTX transmitter and receiver circuits relative to GND	−0.5	1.1	V
MGTAVTT	Analog supply voltage for the GTX transmitter and receiver termination circuits relative to GND	−0.5	1.32	V
MGTAVTTRCAL	Analog supply voltage for the resistor calibration circuit of the GTX transceiver column	−0.5	1.32	V
V _{IN}	Receiver (RXP/RXN) and Transmitter (TXP/TXN) absolute input voltage	−0.5	1.32	V
V _{MGTREFCLK}	Reference clock absolute input voltage	−0.5	1.32	V

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.

Table 14: Recommended Operating Conditions for GTX Transceivers⁽¹⁾⁽²⁾

Symbol	Description	Speed Grade	PLL Frequency	Min	Typ	Max	Units
MGTAVCC	Analog supply voltage for the GTX transmitter and receiver circuits relative to GND	-3, -2 ⁽³⁾	> 2.7 GHz	1.0	1.03	1.06	V
		-3, -2 ⁽³⁾	≤ 2.7 GHz	0.95	1.0	1.06	V
		-1	≤ 2.7 GHz	0.95	1.0	1.06	V
		-1L	≤ 2.7 GHz	0.95	1.0	1.05	V
MGTAVTT	Analog supply voltage for the GTX transmitter and receiver termination circuits relative to GND	All	—	1.14	1.2	1.26	V
MGTAVTTRCAL	Analog supply voltage for the resistor calibration circuit of the GTX transceiver column	All	—	1.14	1.2	1.26	V

Notes:

- Each voltage listed requires the filter circuit described in [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#).
- Voltages are specified for the temperature range of T_j = −40°C to +100°C for all XC devices and T_j = −55°C to +125°C for the XQ devices.
- If a GTX Quad contains transceivers operating with a mixture of PLL frequencies above and below 2.7 GHz, the MGTAVCC voltage supply must be in the range of 1.0V to 1.06V.

Table 15: GTX Transceiver Supply Current (per Lane) ⁽¹⁾⁽²⁾

Symbol	Description	Typ	Max	Units
I _{MGTAVTT}	MGTAVTT supply current for one GTX transceiver	55.9	Note 2	mA
I _{MGTAVCC}	MGTAVCC supply current for one GTX transceiver	56.1		mA
MGTR _{REF}	Precision reference resistor for internal calibration termination	100.0 ± 1% tolerance		Ω

Notes:

- Typical values are specified at nominal voltage, 25°C, with a 3.125 Gb/s line rate.
- Values for currents of other transceiver configurations and conditions can be obtained by using the XPower Estimator (XPE) or XPower Analyzer (XPA) tools.

Table 21: GTX Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range		62.5	–	650	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	–	200	–	ps
T_{FCLK}	Reference clock fall time	80% – 20%	–	200	–	ps
T_{DCREF}	Reference clock duty cycle	Transceiver PLL only	45	50	55	%
T_{LOCK}	Clock recovery frequency acquisition time	Initial PLL lock	–	–	1	ms
T_{PHASE}	Clock recovery phase acquisition time	Lock to data after PLL has locked to the reference clock	–	–	200	μ s

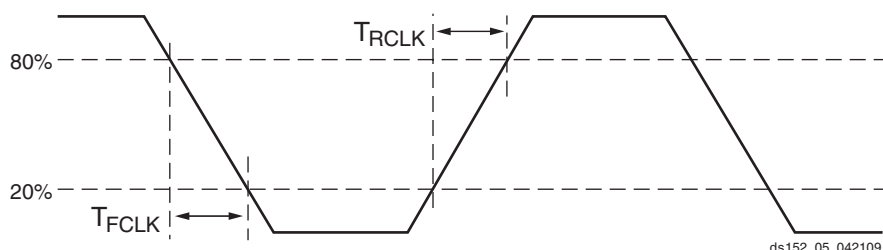


Figure 3: Reference Clock Timing Parameters

Table 22: GTX Transceiver User Clock Switching Characteristics⁽¹⁾

Symbol	Description	Conditions	Speed Grade				Units
			-3	-2	-1	-1L	
F_{TXOUT}	TXOUTCLK maximum frequency	Internal 20-bit data path	330	330	250	250	MHz
		Internal 16-bit data path	412.5	412.5	312.5	250	MHz
F_{RXREC}	RXRECCLK maximum frequency	Internal 20-bit data path	330	330	250	250	MHz
		Internal 16-bit data path	412.5	412.5	312.5	250	MHz
T_{RX}	RXUSRCLK maximum frequency		412.5 ⁽²⁾	412.5 ⁽²⁾	312.5	250	MHz
T_{RX2}	RXUSRCLK2 maximum frequency	1 byte interface	376	376	312.5	250	MHz
		2 byte interface	406.25	406.25	312.5	250	MHz
		4 byte interface	206.25	206.25	156.25	125	MHz
T_{TX}	TXUSRCLK maximum frequency		412.5 ⁽³⁾	412.5 ⁽³⁾	312.5	250	MHz
T_{TX2}	TXUSRCLK2 maximum frequency	1 byte interface	376	376	312.5	250	MHz
		2 byte interface	406.25	406.25	312.5	250	MHz
		4 byte interface	206.25	206.25	156.25	125	MHz

Notes:

1. Clocking must be implemented as described in [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#).
2. 406.25 MHz when the RX elastic buffer is bypassed.
3. 406.25 MHz when the TX buffer is bypassed.

Table 24: GTX Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units
F _{GTXRX}	Serial data rate	RX oversampler not enabled	0.600	–	F _{GTXMAX}	Gb/s
		RX oversampler enabled	0.480	–	0.600	Gb/s
T _{RXELECIDLE}	Time for RXELEC_IDLE to respond to loss or restoration of data		–	75	–	ns
RX _{OOBVDPP}	OOB detect threshold peak-to-peak		60	–	150	mV
RX _{SST}	Receiver spread-spectrum tracking ⁽¹⁾	Modulated @ 33 KHz	–5000	–	0	ppm
RX _{RL}	Run length (CID)	Internal AC capacitor bypassed	–	–	512	UI
RX _{PPMTOL}	Data/REFCLK PPM offset tolerance	CDR 2 nd -order loop disabled	–200	–	200	ppm
		CDR 2 nd -order loop enabled	–2000	–	2000	ppm
SJ Jitter Tolerance ⁽²⁾						
JT_SJ _{6.5}	Sinusoidal Jitter ⁽³⁾	6.5 Gb/s	0.44	–	–	UI
JT_SJ _{5.0}	Sinusoidal Jitter ⁽³⁾	5.0 Gb/s	0.44	–	–	UI
JT_SJ _{4.25}	Sinusoidal Jitter ⁽³⁾	4.25 Gb/s	0.44	–	–	UI
JT_SJ _{3.75}	Sinusoidal Jitter ⁽³⁾	3.75 Gb/s	0.44	–	–	UI
JT_SJ _{3.125}	Sinusoidal Jitter ⁽³⁾	3.125 Gb/s	0.45	–	–	UI
JT_SJ _{3.125L}	Sinusoidal Jitter ⁽³⁾	3.125 Gb/s ⁽⁴⁾	0.45	–	–	UI
JT_SJ _{2.5}	Sinusoidal Jitter ⁽³⁾	2.5 Gb/s ⁽⁵⁾	0.5	–	–	UI
JT_SJ _{1.25}	Sinusoidal Jitter ⁽³⁾	1.25 Gb/s ⁽⁶⁾	0.5	–	–	UI
JT_SJ ₆₀₀	Sinusoidal Jitter ⁽³⁾	600 Mb/s	0.4	–	–	UI
JT_SJ ₄₈₀	Sinusoidal Jitter ⁽³⁾	480 Mb/s	0.4	–	–	UI
SJ Jitter Tolerance with Stressed Eye ⁽²⁾						
JT_TJSE _{3.125}	Total Jitter with Stressed Eye ⁽⁷⁾	3.125 Gb/s	0.70	–	–	UI
		5.0 Gb/s	0.70	–	–	UI
JT_SJSE _{3.125}	Sinusoidal Jitter with Stressed Eye ⁽⁷⁾	3.125 Gb/s	0.1	–	–	UI
		5.0 Gb/s	0.1	–	–	UI

Notes:

- Using PLL_RXDIVSEL_OUT = 1, 2, and 4.
- All jitter values are based on a bit error ratio of 1e^{–12}.
- The frequency of the injected sinusoidal jitter is 80 MHz.
- PLL frequency at 1.5625 GHz and OUTDIV = 1.
- PLL frequency at 2.5 GHz and OUTDIV = 2.
- PLL frequency at 2.5 GHz and OUTDIV = 4.
- Composite jitter with RX equalizer enabled. DFE disabled.

Figure 4 shows the timing parameters in Table 27.

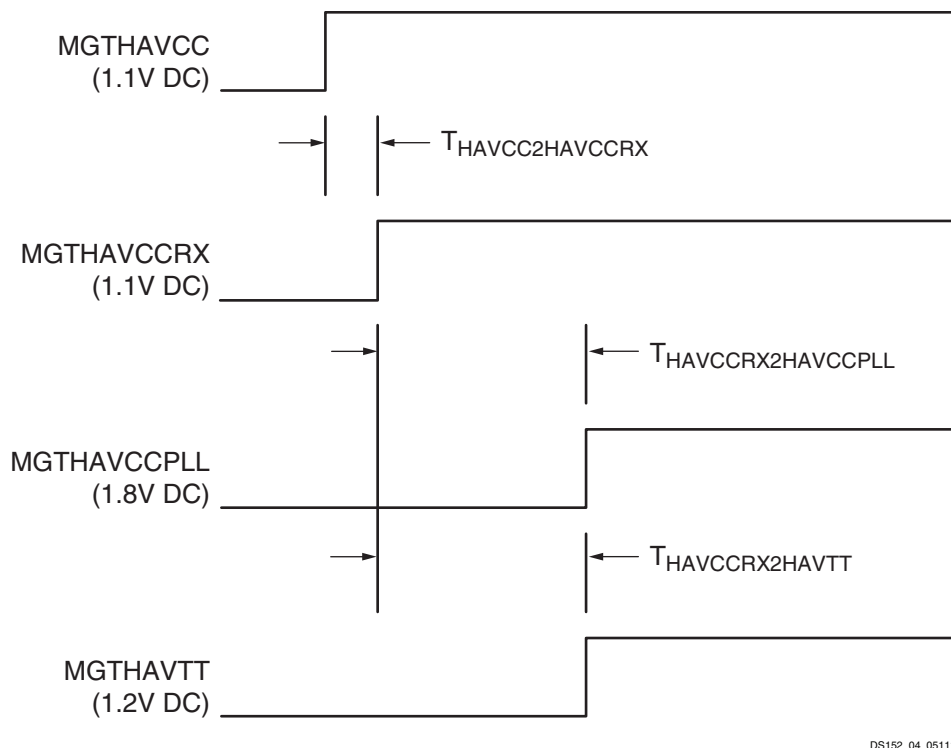


Figure 4: GTH Transceiver Power Supply Power-On Sequencing

Table 28: GTH Transceiver Supply Current

Symbol	Description	Typ ⁽¹⁾	Max	Units
$I_{MGTHAVCC}$	MGTHAVCC supply current for one GTH Quad (4 lanes)	571	Note 2	mA
$I_{MGTHAVCCR}$	MGTHAVCCR supply current for a GTH Quad (4 lanes)	254	Note 2	mA
$I_{MGTHAVTT}$	MGTHAVTT supply current for one GTH Quad (4 lanes)	93	Note 2	mA
$I_{MGTHAVCCPLL}$	MGTHAVCCPLL supply current for one GTH Quad (4 lanes)	219	Note 2	mA
$MGTR_{REF}$	Precision reference resistor for internal calibration termination	1000.0 ± 1% tolerance		Ω

Notes:

- Typical values are specified at nominal voltage, 25°C, with a 10.3125 Gb/s line rate.
- Values for currents other than the values specified in this table can be obtained by using the XPower Estimator (XPE) or XPower Analyzer (XPA) tools.

Table 29: GTH Transceiver Quiescent Supply Current⁽¹⁾⁽²⁾

Symbol	Description	Typ ⁽³⁾	Max	Units
$I_{MGTHAVCCQ}$	Quiescent MGTHAVCC Supply Current for one GTH Quad (4 lanes)	65	Note 4	mA
$I_{MGTHAVCCRQ}$	Quiescent MGTHAVCCR Supply Current for one GTH Quad (4 lanes)	17	Note 4	mA
$I_{MGTHAVTTQ}$	Quiescent MGTHAVTT Supply Current for one GTH Quad (4 lanes)	1	Note 4	mA
$I_{MGTHAVCCPLLQ}$	Quiescent MGTHAVCCPLL Supply Current for one GTH Quad (4 lanes)	1	Note 4	mA

Notes:

- Device powered and unconfigured.
- GTH transceiver quiescent supply current for an entire device can be calculated by multiplying the values in this table by the number of available GTH transceivers.
- Typical values are specified at nominal voltage, 25°C.
- Currents for conditions other than values specified in this table can be obtained by using the XPE or XPA tools.

GTH Transceiver Switching Characteristics

Consult [UG371: Virtex-6 FPGA GTH Transceivers User Guide](#) for further information.

Table 32: GTH Transceiver Maximum Data Rate and PLL Frequency Range

Symbol	Description	Conditions	Speed Grade			Units
			-3	-2	-1	
F_{GTHMAX}	Maximum GTH transceiver data rate	PLL Output Divider = 1	11.182	11.182	10.32	Gb/s
		PLL Output Divider = 4	2.795	2.795	2.58	Gb/s
F_{GTHMIN}	Minimum GTH transceiver data rate ⁽¹⁾	PLL Output Divider = 1	9.92	9.92	9.92	Gb/s
		PLL Output Divider = 4	2.48	2.48	2.48	Gb/s
$F_{GPLLMAX}$	Maximum GTH PLL frequency		5.591	5.591	5.16	GHz
$F_{GPLLMIN}$	Minimum GTH PLL frequency		4.96	4.96	4.96	GHz

Notes:

- Lower data rates can be achieved using FPGA logic based oversampling designs.

Table 33: GTH Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2	-1	
$F_{GTHDRPCLK}$	GTHDRPCLK maximum frequency	70	70	60	MHz

Table 34: GTH Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range	-1 speed grade	150	—	645	MHz
		-2 and -3 speed grades	150	—	700	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	—	200	—	ps
T_{FCLK}	Reference clock fall time	80% – 20%	—	200	—	ps
T_{DCREF}	Reference clock duty cycle	CLK	45	50	55	%
T_{LOCK}	Clock recovery frequency acquisition time	Initial PLL lock	—	—	2	ms
T_{PHASE}	Clock recovery phase acquisition time	Lock to data after PLL has locked to the reference clock	—	—	20	μs

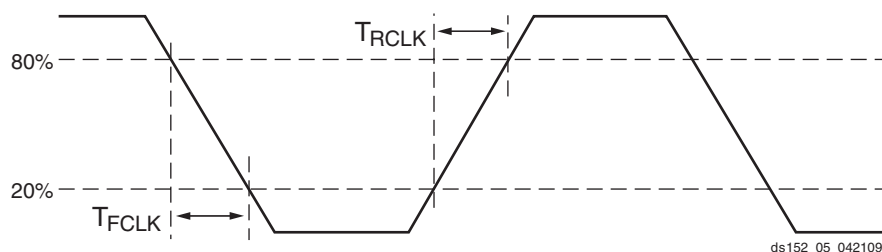


Figure 5: Reference Clock Timing Parameters

Table 35: GTH Transceiver User Clock Switching Characteristics ⁽¹⁾

Symbol	Description	Conditions	Speed Grade			Units
			-3	-2	-1	
F _{TXOUT}	TXUSERCLKOUT maximum frequency		350	350	323	MHz
F _{RXOUT}	RXUSERCLKOUT maximum frequency		350	350	323	MHz
F _{TXIN}	TXUSERCLKIN maximum frequency	16-bit data path	350	350	323	MHz
		20-bit data path	280	280	258	MHz
		32-bit data path	350	350	323	MHz
		40-bit data path	280	280	258	MHz
		64-bit data path	175	175	162	MHz
		80-bit data path	140	140	129	MHz
		64B/66B-bit data path	170	170	157	MHz
F _{RXIN}	RXUSERCLKIN maximum frequency	16-bit data path	350	350	323	MHz
		20-bit data path	280	280	258	MHz
		32-bit data path	350	350	323	MHz
		40-bit data path	280	280	258	MHz
		64-bit data path	175	175	162	MHz
		80-bit data path	140	140	129	MHz
		64B/66B-bit data path	170	170	157	MHz

Notes:

1. Clocking must be implemented as described in [UG371](#): Virtex-6 FPGA GTH Transceivers User Guide.

Table 36: GTH Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
T _{RTX}	TX Rise time	20%–80%	–	50 ⁽³⁾	–	ps
T _{FTX}	TX Fall time	80%–20%	–	50 ⁽³⁾	–	ps
T _{LLSKEW}	TX lane-to-lane skew	within one GTH Quad	–	–	300	ps
Transmitter Output Jitter⁽¹⁾⁽²⁾						
TJ _{11.18}	Total Jitter	11.181 Gb/s	–	–	0.280	UI
DJ _{11.18}	Deterministic Jitter		–	–	0.170	UI
TJ _{10.3125}	Total Jitter	10.3125 Gb/s	–	–	0.280	UI
DJ _{10.3125}	Deterministic Jitter		–	–	0.170	UI
TJ _{9.953}	Total Jitter	9.953 Gb/s	–	–	0.280	UI
DJ _{9.953}	Deterministic Jitter		–	–	0.170	UI
TJ _{2.667}	Total Jitter	2.667 Gb/s	–	–	0.110	UI
DJ _{2.667}	Deterministic Jitter		–	–	0.060	UI
TJ _{2.488}	Total Jitter	2.488 Gb/s	–	–	0.110	UI
DJ _{2.488}	Deterministic Jitter		–	–	0.060	UI

Notes:

1. These values are NOT intended for protocol specific compliance determinations.
2. All jitter values are based on a bit-error ratio of 1e⁻¹².
3. Rise and fall times are specified at the transmitter package balls.

Table 44: IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L	
LVC MOS25, Fast, 24 mA	0.51	0.57	0.66	0.70	1.66	1.79	1.99	1.96	1.66	1.79	1.99	1.96	ns
LVC MOS18, Slow, 2 mA	0.55	0.61	0.71	0.73	4.21	4.47	4.87	4.30	4.21	4.47	4.87	4.30	ns
LVC MOS18, Slow, 4 mA	0.55	0.61	0.71	0.73	2.79	2.96	3.21	2.94	2.79	2.96	3.21	2.94	ns
LVC MOS18, Slow, 6 mA	0.55	0.61	0.71	0.73	2.30	2.43	2.64	2.47	2.30	2.43	2.64	2.47	ns
LVC MOS18, Slow, 8 mA	0.55	0.61	0.71	0.73	2.01	2.11	2.27	2.24	2.01	2.11	2.27	2.24	ns
LVC MOS18, Slow, 12 mA	0.55	0.61	0.71	0.73	1.88	1.99	2.15	2.10	1.88	1.99	2.15	2.10	ns
LVC MOS18, Slow, 16 mA	0.55	0.61	0.71	0.73	1.84	1.95	2.11	2.04	1.84	1.95	2.11	2.04	ns
LVC MOS18, Fast, 2 mA	0.55	0.61	0.71	0.73	4.00	4.23	4.57	4.08	4.00	4.23	4.57	4.08	ns
LVC MOS18, Fast, 4 mA	0.55	0.61	0.71	0.73	2.62	2.76	2.97	2.74	2.62	2.76	2.97	2.74	ns
LVC MOS18, Fast, 6 mA	0.55	0.61	0.71	0.73	2.15	2.28	2.46	2.32	2.15	2.28	2.46	2.32	ns
LVC MOS18, Fast, 8 mA	0.55	0.61	0.71	0.73	1.90	1.99	2.13	2.14	1.90	1.99	2.13	2.14	ns
LVC MOS18, Fast, 12 mA	0.55	0.61	0.71	0.73	1.69	1.80	1.97	1.88	1.69	1.80	1.97	1.88	ns
LVC MOS18, Fast, 16 mA	0.55	0.61	0.71	0.73	1.63	1.74	1.91	1.88	1.63	1.74	1.91	1.88	ns
LVC MOS15, Slow, 2 mA	0.64	0.73	0.85	0.85	3.43	3.77	4.29	3.91	3.43	3.77	4.29	3.91	ns
LVC MOS15, Slow, 4 mA	0.64	0.73	0.85	0.85	2.58	2.79	3.10	2.93	2.58	2.79	3.10	2.93	ns
LVC MOS15, Slow, 6 mA	0.64	0.73	0.85	0.85	2.08	2.32	2.68	2.50	2.08	2.32	2.68	2.50	ns
LVC MOS15, Slow, 8 mA	0.64	0.73	0.85	0.85	1.81	1.98	2.23	2.24	1.81	1.98	2.23	2.24	ns
LVC MOS15, Slow, 12 mA	0.64	0.73	0.85	0.85	1.76	1.91	2.13	2.07	1.76	1.91	2.13	2.07	ns
LVC MOS15, Slow, 16 mA	0.64	0.73	0.85	0.85	1.69	1.83	2.04	1.98	1.69	1.83	2.04	1.98	ns
LVC MOS15, Fast, 2 mA	0.64	0.73	0.85	0.85	3.44	3.77	4.28	3.91	3.44	3.77	4.28	3.91	ns
LVC MOS15, Fast, 4 mA	0.64	0.73	0.85	0.85	2.37	2.53	2.78	2.66	2.37	2.53	2.78	2.66	ns
LVC MOS15, Fast, 6 mA	0.64	0.73	0.85	0.85	1.80	2.05	2.42	2.16	1.80	2.05	2.42	2.16	ns
LVC MOS15, Fast, 8 mA	0.64	0.73	0.85	0.85	1.76	1.90	2.11	2.04	1.76	1.90	2.11	2.04	ns
LVC MOS15, Fast, 12 mA	0.64	0.73	0.85	0.85	1.64	1.77	1.97	1.90	1.64	1.77	1.97	1.90	ns
LVC MOS15, Fast, 16 mA	0.64	0.73	0.85	0.85	1.62	1.76	1.96	1.92	1.62	1.76	1.96	1.92	ns
LVC MOS12, Slow, 2 mA	0.72	0.81	0.93	0.95	3.14	3.39	3.75	3.54	3.14	3.39	3.75	3.54	ns
LVC MOS12, Slow, 4 mA	0.72	0.81	0.93	0.95	2.43	2.63	2.93	2.79	2.43	2.63	2.93	2.79	ns
LVC MOS12, Slow, 6 mA	0.72	0.81	0.93	0.95	1.92	2.11	2.41	2.26	1.92	2.11	2.41	2.26	ns
LVC MOS12, Slow, 8 mA	0.72	0.81	0.93	0.95	1.87	2.02	2.25	2.17	1.87	2.02	2.25	2.17	ns
LVC MOS12, Fast, 2 mA	0.72	0.81	0.93	0.95	2.71	2.98	3.39	3.11	2.71	2.98	3.39	3.11	ns
LVC MOS12, Fast, 4 mA	0.72	0.81	0.93	0.95	1.93	2.16	2.51	2.31	1.93	2.16	2.51	2.31	ns
LVC MOS12, Fast, 6 mA	0.72	0.81	0.93	0.95	1.75	1.89	2.11	2.05	1.75	1.89	2.11	2.05	ns
LVC MOS12, Fast, 8 mA	0.72	0.81	0.93	0.95	1.69	1.82	2.02	1.98	1.69	1.82	2.02	1.98	ns
LVDCI_25	0.51	0.57	0.66	0.70	2.05	2.14	2.26	2.26	2.05	2.14	2.26	2.26	ns
LVDCI_18	0.55	0.61	0.71	0.73	2.07	2.23	2.47	2.38	2.07	2.23	2.47	2.38	ns
LVDCI_15	0.64	0.73	0.85	0.85	1.85	2.01	2.24	2.18	1.85	2.01	2.24	2.18	ns

Table 44: IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L	
DIFF_SSTL18_I	0.85	0.94	1.09	1.08	1.47	1.58	1.75	1.73	1.47	1.58	1.75	1.73	ns
DIFF_SSTL18_I_DCI	0.85	0.94	1.09	1.08	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns
DIFF_SSTL18_II	0.85	0.94	1.09	1.08	1.39	1.50	1.67	1.66	1.39	1.50	1.67	1.66	ns
DIFF_SSTL18_II_DCI	0.85	0.94	1.09	1.08	1.36	1.47	1.63	1.62	1.36	1.47	1.63	1.62	ns
DIFF_SSTL18_II_T_DCI	0.85	0.94	1.09	1.08	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns
DIFF_SSTL15	0.81	0.91	1.06	1.06	1.42	1.54	1.71	1.69	1.42	1.54	1.71	1.69	ns
DIFF_SSTL15_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns
DIFF_SSTL15_T_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units
	Speed Grade			Speed Grade			Speed Grade			
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L	
LVDS_25	0.94	1.09	1.08	1.54	2.16	1.62	1.54	2.16	1.62	ns
LVDSEXT_25	0.94	1.09	1.08	1.65	2.20	1.73	1.65	2.20	1.73	ns
HT_25	0.94	1.09	1.08	1.62	2.20	1.69	1.62	2.20	1.69	ns
BLVDS_25	0.94	1.09	1.08	1.50	3.18	1.65	1.50	3.18	1.65	ns
RSDS_25 (point to point)	0.94	1.09	1.08	1.54	2.22	1.62	1.54	2.22	1.62	ns
HSTL_I	0.91	1.06	1.06	1.56	2.44	1.71	1.56	2.44	1.71	ns
HSTL_II	0.91	1.06	1.06	1.56	2.21	1.72	1.56	2.21	1.72	ns
HSTL_III	0.91	1.06	1.06	1.54	2.50	1.69	1.54	2.50	1.69	ns
HSTL_I_18	0.91	1.06	1.06	1.58	2.43	1.72	1.58	2.43	1.72	ns
HSTL_II_18	0.91	1.06	1.06	1.62	2.30	1.78	1.62	2.30	1.78	ns
HSTL_III_18	0.91	1.06	1.06	1.54	2.49	1.69	1.54	2.49	1.69	ns
SSTL2_I	0.91	1.06	1.06	1.60	2.50	1.74	1.60	2.50	1.74	ns
SSTL2_II	0.91	1.06	1.06	1.54	2.49	1.71	1.54	2.49	1.71	ns
SSTL15	0.91	1.06	1.06	1.54	2.07	1.69	1.54	2.07	1.69	ns
LVC MOS25, Slow, 2 mA	0.57	0.66	0.70	5.46	6.01	5.63	5.46	6.01	5.63	ns
LVC MOS25, Slow, 4 mA	0.57	0.66	0.70	3.49	3.79	3.65	3.49	3.79	3.65	ns
LVC MOS25, Slow, 6 mA	0.57	0.66	0.70	2.81	3.08	2.95	2.81	3.08	2.95	ns
LVC MOS25, Slow, 8 mA	0.57	0.66	0.70	2.41	2.72	2.59	2.41	2.72	2.59	ns
LVC MOS25, Slow, 12 mA	0.57	0.66	0.70	1.95	2.23	2.10	1.95	2.23	2.10	ns
LVC MOS25, Slow, 16 mA	0.57	0.66	0.70	2.05	2.29	2.21	2.05	2.29	2.21	ns
LVC MOS25, Slow, 24 mA	0.57	0.66	0.70	1.82	2.24	1.98	1.82	2.24	1.98	ns
LVC MOS25, Fast, 2 mA	0.57	0.66	0.70	5.49	6.04	5.62	5.49	6.04	5.62	ns
LVC MOS25, Fast, 4 mA	0.57	0.66	0.70	3.50	3.82	3.65	3.50	3.82	3.65	ns
LVC MOS25, Fast, 6 mA	0.57	0.66	0.70	2.73	2.99	2.88	2.73	2.99	2.88	ns
LVC MOS25, Fast, 8 mA	0.57	0.66	0.70	2.33	2.65	2.53	2.33	2.65	2.53	ns
LVC MOS25, Fast, 12 mA	0.57	0.66	0.70	1.88	2.08	2.03	1.88	2.08	2.03	ns

Table 58: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
$T_{\text{DSPDCK_RSTP_PREG}} / T_{\text{DSPCKD_RSTP_PREG}}$	RSTP input to P register CLK	0.26/ 0.04	0.30/ 0.04	0.35/ 0.05	0.35/ 0.05	0.43/ 0.06	ns
Combinatorial Delays from Input Pins to Output Pins							
$T_{\text{DSPDO_}\{A, B\}_ \{P, \text{CARRYOUT}\}_ \text{MULT}}$	{A, B} input to {P, CARRYOUT} output using multiplier	3.76	4.29	5.08	5.08	5.87	ns
$T_{\text{DSPDO_D_}\{P, \text{CARRYOUT}\}_ \text{MULT}}$	D input to {P, CARRYOUT} output using multiplier	3.57	4.07	4.82	4.82	5.57	ns
$T_{\text{DSPDO_}\{A, B\}_ \{P, \text{CARRYOUT}\}}$	{A, B} input to {P, CARRYOUT} output not using multiplier	1.55	1.76	2.07	2.07	2.41	ns
$T_{\text{DSPDO_}\{C, \text{CARRYIN}\}_ \{P, \text{CARRYOUT}\}}$	{C, CARRYIN} input to {P, CARRYOUT} output	1.38	1.56	1.83	1.83	2.13	ns
Combinatorial Delays from Input Pins to Cascading Output Pins							
$T_{\text{DSPDO_}\{A, B\}_ \{ACOUT, BCOUT\}}$	{A, B} input to {ACOUT, BCOUT} output	0.49	0.56	0.65	0.65	0.73	ns
$T_{\text{DSPDO_}\{A, B\}_ \{PCOUT, \text{CARRYCASCOUT}, \text{MULTSIGNOUT}\}_ \text{MULT}}$	{A, B} input to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output using multiplier	3.87	4.42	5.24	5.24	6.09	ns
$T_{\text{DSPDO_D_}\{PCOUT, \text{CARRYCASCOUT}, \text{MULTSIGNOUT}\}_ \text{MULT}}$	D input to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output using multiplier	3.66	4.17	4.94	4.94	5.76	ns
$T_{\text{DSPDO_}\{A, B\}_ \{PCOUT, \text{CARRYCASCOUT}, \text{MULTSIGNOUT}\}}$	{A, B} input to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output not using multiplier	1.64	1.86	2.19	2.19	2.60	ns
$T_{\text{DSPDO_}\{C, \text{CARRYIN}\}_ \{PCOUT, \text{CARRYCASCOUT}, \text{MULTSIGNOUT}\}}$	{C, CARRYIN} input to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	1.46	1.66	1.95	1.95	2.32	ns
Combinatorial Delays from Cascading Input Pins to All Output Pins							
$T_{\text{DSPDO_}\{ACIN, BCIN\}_ \{P, \text{CARRYOUT}\}_ \text{MULT}}$	{ACIN, BCIN} input to {P, CARRYOUT} output using multiplier	3.67	4.19	4.97	4.97	5.75	ns
$T_{\text{DSPDO_}\{ACIN, BCIN\}_ \{P, \text{CARRYOUT}\}}$	{ACIN, BCIN} input to {P, CARRYOUT} output not using multiplier	1.43	1.63	1.92	1.92	2.25	ns
$T_{\text{DSPDO_}\{ACIN, BCIN\}_ \{ACOUT, BCOUT\}}$	{ACIN, BCIN} input to {ACOUT, BCOUT} output	0.36	0.42	0.49	0.49	0.56	ns
$T_{\text{DSPDO_}\{ACIN, BCIN\}_ \{PCOUT, \text{CARRYCASCOUT}, \text{MULTSIGNOUT}\}_ \text{MULT}}$	{ACIN, BCIN} input to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output using multiplier	3.76	4.29	5.10	5.10	5.94	ns
$T_{\text{DSPDO_}\{ACIN, BCIN\}_ \{PCOUT, \text{CARRYCASCOUT}, \text{MULTSIGNOUT}\}}$	{ACIN, BCIN} input to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output not using multiplier	1.52	1.73	2.05	2.05	2.44	ns
$T_{\text{DSPDO_}\{PCIN, \text{CARRYCASCIN}, \text{MULTSIGNIN}\}_ \{P, \text{CARRYOUT}\}}$	{PCIN, CARRYCASCIN, MULTSIGNIN} input to {P, CARRYOUT} output	1.19	1.35	1.60	1.60	1.87	ns

Table 59: Configuration Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T _{SMCKBY}	CCLK to BUSY out in readback at 2.5V	6	6	6	7	ns, Max
	CCLK to BUSY out in readback at 1.8V	6	6	6	7	ns, Max
F _{SMCK}	Maximum Frequency with respect to nominal CCLK	100	100	100	70	MHz, Max
F _{RBCK}	Maximum Readback Frequency with respect to nominal CCLK	100	100	100	60	MHz, Max
F _{MCCKTOL}	Frequency tolerance, master mode with respect to nominal CCLK	55	55	55	60	%
Boundary-Scan Port Timing Specifications						
T _{TAPTCK} /T _{TCKTAP}	TMS and TDI Setup time before TCK/ Hold time after TCK	3.0/2.0	3.0/2.0	3.0/2.0	4.0/2.0	ns, Min
T _{TCKTDO}	TCK falling edge to TDO output valid at 2.5V	6	6	6	7	ns, Max
	TCK falling edge to TDO output valid at 1.8V	6	6	6	7	ns, Max
F _{TCK}	Maximum configuration TCK clock frequency	66	66	66	33	MHz, Max
F _{TCKB_MIN}	Minimum boundary-scan TCK clock frequency when using IEEE Std 1149.6 (AC-JTAG). Minimum operating temperature for IEEE Std 1149.6 is 0°C.	15	15	15	15	MHz, Min
F _{TCKB}	Maximum boundary-scan TCK clock frequency	66	66	66	33	MHz, Max
BPI Master Flash Mode Programming Switching						
T _{BPICCO} ⁽²⁾	ADDR[25:0], RS[1:0], FCS_B, FOE_B, FWE_B outputs valid after CCLK rising edge at 2.5V	6	6	6	7	ns
	ADDR[25:0], RS[1:0], FCS_B, FOE_B, FWE_B outputs valid after CCLK rising edge at 1.8V	6	6	6	7	ns
T _{BPIDCC} /T _{BPICCD}	Setup/Hold on D[15:0] data input pins	4.0/0.0	4.0/0.0	4.0/0.0	5.0/0.0	ns
T _{INITADDR}	Minimum period of initial ADDR[25:0] address cycles	3	3	3	3	CCLK cycles
SPI Master Flash Mode Programming Switching						
T _{SPIDCC} /T _{SPIDCCD}	DIN Setup/Hold before/after the rising CCLK edge	3.0/0.0	3.0/0.0	3.0/0.0	3.5/0.0	ns
T _{SPICCM}	MOSI clock to out at 2.5V	6	6	6	7	ns
	MOSI clock to out at 1.8V	6	6	6	7	ns
T _{SPICFC}	FCS_B clock to out at 2.5V	6	6	6	7	ns
	FCS_B clock to out at 1.8V	6	6	6	7	ns
T _{FSINIT} /T _{FSINITH}	FS[2:0] to INIT_B rising edge Setup and Hold	2	2	2	2	µs
CCLK Output (Master Modes)						
T _{MCCKL}	Master CCLK clock Low time duty cycle	45/55	45/55	45/55	40/60	%, Min/Max
T _{MCCKH}	Master CCLK clock High time duty cycle	45/55	45/55	45/55	40/60	%, Min/Max
CCLK Input (Slave Modes)						
T _{SCCKL}	Slave CCLK clock minimum Low time	2.5	2.5	2.5	2.5	ns, Min
T _{SCCKH}	Slave CCLK clock minimum High time	2.5	2.5	2.5	2.5	ns, Min
Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK						
F _{DCK}	Maximum frequency for DCLK	200	200	200	200	MHz
T _{MMCMCKD_DADDR} / T _{MMCMCKD_DADDR}	DADDR Setup/Hold	1.25/ 0.00	1.40/ 0.00	1.63/ 0.00	1.64/ 0.00	ns

Table 62: Regional Clock Switching Characteristics (BUFR) (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T _{BRDO_O}	Propagation delay from CLR to O	0.69	0.74	0.80	1.12	ns
Maximum Frequency						
F _{MAX} ⁽¹⁾	Regional clock tree (BUFR)	500	420	300	300	MHz

Notes:

1. The maximum input frequency to the BUFR is the BUFIO F_{MAX} frequency.

Table 63: Horizontal Clock Buffer Switching Characteristics (BUFH)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
T _{BHCKO_O}	BUFH delay from I to O	0.10	0.11	0.13	0.15	ns
T _{BHCK_CE} /T _{BHCKC_CE}	CE pin Setup and Hold	0.04/ 0.04	0.04/ 0.04	0.05/ 0.05	0.04/ 0.04	ns
Maximum Frequency						
F _{MAX}	Horizontal clock buffer (BUFH)	800	750	700	667	MHz

MMCM Switching Characteristics

Table 64: MMCM Specification

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
F _{INMAX}	Maximum Input Clock Frequency ⁽¹⁾	800	750	700	700	MHz
F _{INMIN}	Minimum Input Clock Frequency	10	10	10	10	MHz
F _{INJITTER}	Maximum Input Clock Period Jitter	< 20% of clock input period or 1 ns Max				
F _{INDUTY} ⁽²⁾	Allowable Input Duty Cycle: 10—49 MHz	25/75				%
	Allowable Input Duty Cycle: 50—199 MHz	30/70				%
	Allowable Input Duty Cycle: 200—399 MHz	35/65				%
	Allowable Input Duty Cycle: 400—499 MHz	40/60				%
	Allowable Input Duty Cycle: >500 MHz	45/55				%
F _{MIN_PSCLK}	Minimum Dynamic Phase Shift Clock Frequency	0.01	0.01	0.01	0.01	MHz
F _{MAX_PSCLK}	Maximum Dynamic Phase Shift Clock Frequency	550	500	450	450	MHz
F _{VCOMIN}	Minimum MMCM VCO Frequency	600	600	600	600	MHz
F _{VCOMAX}	Maximum MMCM VCO Frequency	1600	1440	1200	1200	MHz
F _{BANDWIDTH}	Low MMCM Bandwidth at Typical ⁽³⁾	1.00	1.00	1.00	1.00	MHz
	High MMCM Bandwidth at Typical ⁽³⁾	4.00	4.00	4.00	4.00	MHz
T _{STATPHAOFFSET}	Static Phase Offset of the MMCM Outputs ⁽⁴⁾	0.12	0.12	0.12	0.12	ns
T _{OUTJITTER}	MMCM Output Jitter ⁽⁵⁾	Note 3				
T _{OUTDUTY}	MMCM Output Clock Duty Cycle Precision ⁽⁶⁾	0.15	0.20	0.20	0.20	ns
T _{LOCKMAX}	MMCM Maximum Lock Time	100	100	100	100	μs
F _{OUTMAX}	MMCM Maximum Output Frequency	800	750	700	700	MHz
F _{OUTMIN}	MMCM Minimum Output Frequency ⁽⁷⁾⁽⁸⁾	4.69	4.69	4.69	4.69	MHz
T _{EXTFDVAR}	External Clock Feedback Variation	< 20% of clock input period or 1 ns Max				

Table 64: MMCM Specification (Cont'd)

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
RST _{MINPULSE}	Minimum Reset Pulse Width	1.5	1.5	1.5	1.5	ns
F _{PFDMAX}	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to High or Optimized ⁽⁹⁾	550	500	450	450	MHz
	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to Low	300	300	300	300	MHz
F _{PFDMIN}	Minimum Frequency at the Phase Frequency Detector with Bandwidth Set to High or Optimized	135	135	135	135	MHz
	Minimum Frequency at the Phase Frequency Detector with Bandwidth Set to Low	10	10	10	10	MHz
T _{FBDELAY}	Maximum Delay in the Feedback Path	3 ns Max or one CLKIN cycle				
T _{MMCMCK_PSEN} / T _{MMCMCKD_PSEN}	Setup and Hold of Phase Shift Enable	1.04 0.00	1.04 0.00	1.04 0.00	1.04 0.00	ns
T _{MMCMCK_PINCDEC} / T _{MMCMCKD_PINCDEC}	Setup and Hold of Phase Shift Increment/Decrement	1.04 0.00	1.04 0.00	1.04 0.00	1.04 0.00	ns
T _{MMCMCKO_PSDONE}	Phase Shift Clock-to-Out of PSDONE	0.32	0.34	0.38	0.38	ns

Notes:

- When DIVCLK_DIVIDE = 3 or 4, F_{INMAX} is 315 MHz.
- This duty cycle specification does not apply to the GTH_QUAD (GTH) to MMCM connection. The GTH transceivers drive the MMCMs at the following maximum frequencies: 323 MHz for -1 speed grade devices, 350 MHz for -2 speed grade devices, or 350 MHz for -3 speed grade devices.
- The MMCM does not filter typical spread-spectrum input clocks because they are usually far below the bandwidth filter frequencies.
- The static offset is measured between any MMCM outputs with identical phase.
- Values for this parameter are available in the Clocking Wizard.
See http://www.xilinx.com/products/intellectual-property/clocking_wizard.htm.
- Includes global clock buffer.
- Calculated as F_{VCO}/128 assuming output duty cycle is 50%.
- When CASCADE4_OUT = TRUE, F_{OUTMIN} is 0.036 MHz.
- In ISE software 12.3 (or earlier versions supporting the Virtex-6 family), the phase frequency detector Optimized bandwidth setting is equivalent to the High bandwidth setting. Starting with ISE software 12.4, the Optimized bandwidth setting is automatically adjusted to Low when the software can determine that the phase frequency detector input is less than 135 MHz.

Virtex-6 Device Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. The representative values for typical pin locations and normal clock loading are listed in Table 65. Values are expressed in nanoseconds unless otherwise noted.

Table 65: Global Clock Input to Output Delay Without MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>without</i> MMCM.							
T _{ICKOF}	Global Clock input and OUTFF <i>without</i> MMCM	XC6VLX75T	4.91	5.32	5.88	6.02	ns
		XC6VLX130T	4.89	5.33	6.00	6.13	ns
		XC6VLX195T	5.02	5.46	6.13	6.27	ns
		XC6VLX240T	5.02	5.46	6.13	6.27	ns
		XC6VLX365T	5.30	5.75	6.43	6.37	ns
		XC6VLX550T	N/A	6.02	6.72	6.60	ns
		XC6VLX760	N/A	6.26	6.97	6.87	ns
		XC6VSX315T	5.40	5.85	6.54	6.49	ns
		XC6VSX475T	N/A	6.01	6.71	6.61	ns
		XC6VHX250T	5.18	5.63	6.30	N/A	ns
		XC6VHX255T	5.20	5.66	6.34	N/A	ns
		XC6VHX380T	5.38	5.84	6.53	N/A	ns
		XC6VHX565T	N/A	6.03	6.71	N/A	ns
		XQ6VLX130T	N/A	5.33	6.00	6.13	ns
		XQ6VLX240T	N/A	5.46	6.13	6.27	ns
		XQ6VLX550T	N/A	N/A	6.72	6.60	ns
		XQ6VSX315T	N/A	5.85	6.54	6.49	ns
		XQ6VSX475T	N/A	N/A	6.71	6.61	ns

Notes:

- Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

Virtex-6 Device Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. The representative values for typical pin locations and normal clock loading are listed in Table 68. Values are expressed in nanoseconds unless otherwise noted.

Table 68: Global Clock Input Setup and Hold Without MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMOS25 Standard. ⁽¹⁾							
T _{PSFD} / T _{PHFD}	Full Delay (Legacy Delay or Default Delay) Global Clock Input and IFF ⁽²⁾ without MMCM	XC6VLX75T	1.33/ 0.03	1.44/ 0.03	1.75/ 0.03	2.18/ −0.22	ns
		XC6VLX130T	1.31/ −0.08	1.54/ −0.08	1.88/ −0.08	2.31/ −0.12	ns
		XC6VLX195T	1.36/ −0.11	1.60/ −0.11	1.97/ −0.11	2.40/ −0.25	ns
		XC6VLX240T	1.36/ −0.11	1.60/ −0.11	1.97/ −0.11	2.40/ −0.25	ns
		XC6VLX365T	1.79/ −0.28	1.87/ −0.28	2.17/ −0.28	2.48/ −0.24	ns
		XC6VLX550T	N/A	2.22/ −0.12	2.36/ −0.12	2.77/ −0.26	ns
		XC6VLX760	N/A	2.19/ −0.24	2.35/ −0.24	2.71/ −0.21	ns
		XC6VSX315T	1.75/ −0.09	1.85/ −0.09	2.06/ −0.09	2.47/ −0.24	ns
		XC6VSX475T	N/A	2.14/ −0.14	2.31/ −0.14	2.71/ −0.30	ns
		XC6VHX250T	1.93/ −0.22	2.04/ −0.22	2.25/ −0.22	N/A	ns
		XC6VHX255T	1.81/ −0.33	2.11/ −0.33	2.56/ −0.33	N/A	ns
		XC6VHX380T	1.93/ −0.11	2.04/ −0.11	2.25/ −0.11	N/A	ns
		XC6VHX565T	N/A	2.20/ −0.12	2.39/ −0.12	N/A	ns
		XQ6VLX130T	N/A	1.54/ −0.08	1.88/ −0.08	2.31/ −0.12	ns
		XQ6VLX240T	N/A	1.60/ −0.11	1.97/ −0.11	2.40/ −0.25	ns
		XQ6VLX550T	N/A	N/A	2.36/ −0.12	2.77/ −0.26	ns
		XQ6VSX315T	N/A	1.85/ −0.09	2.06/ −0.09	2.47/ −0.24	ns
		XQ6VSX475T	N/A	N/A	2.31/ −0.14	2.71/ −0.30	ns

Notes:

- Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
- IFF = Input Flip-Flop or Latch
- A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.

Clock Switching Characteristics

The parameters in this section provide the necessary values for calculating timing budgets for Virtex-6 FPGA clock transmitter and receiver data-valid windows.

Table 71: Duty Cycle Distortion and Clock-Tree Skew

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
T_{DCD_CLK}	Global Clock Tree Duty Cycle Distortion ⁽¹⁾	All	0.12	0.12	0.12	0.12	ns
T_{CKSKEW}	Global Clock Tree Skew ⁽²⁾	XC6VLX75T	0.15	0.16	0.18	0.17	ns
		XC6VLX130T	0.25	0.26	0.29	0.28	ns
		XC6VLX195T	0.26	0.27	0.31	0.30	ns
		XC6VLX240T	0.26	0.27	0.31	0.30	ns
		XC6VLX365T	0.28	0.29	0.31	0.31	ns
		XC6VLX550T	N/A	0.50	0.54	0.54	ns
		XC6VLX760	N/A	0.51	0.56	0.56	ns
		XC6VSX315T	0.27	0.28	0.32	0.30	ns
		XC6VSX475T	N/A	0.39	0.44	0.42	ns
		XC6VHX250T	0.25	0.26	0.29	N/A	ns
		XC6VHX255T	0.35	0.37	0.41	N/A	ns
		XC6VHX380T	0.45	0.47	0.52	N/A	ns
		XC6VHX565T	N/A	0.46	0.51	N/A	ns
		XQ6VLX130T	N/A	0.26	0.29	0.28	ns
		XQ6VLX240T	N/A	0.27	0.31	0.30	ns
		XQ6VLX550T	N/A	N/A	0.54	0.54	ns
		XQ6VSX315T	N/A	0.28	0.32	0.30	ns
		XQ6VSX475T	N/A	N/A	0.44	0.42	ns
T_{DCD_BUFIO}	I/O clock tree duty cycle distortion	All	0.08	0.08	0.08	0.08	ns
T_{BUFIO_SKEW}	I/O clock tree skew across one clock region	All	0.03	0.03	0.03	0.02	ns
T_{BUFIO_SKEW2}	I/O clock tree skew across three clock regions	All	0.10	0.12	0.23	0.12	ns
T_{DCD_BUFR}	Regional clock tree duty cycle distortion	All	0.15	0.15	0.15	0.15	ns

Notes:

- These parameters represent the worst-case duty cycle distortion observable at the pins of the device using LVDS output buffers. For cases where other I/O standards are used, IBIS can be used to calculate any additional duty cycle distortion that might be caused by asymmetrical rise/fall times.
- The T_{CKSKEW} value represents the worst-case clock-tree skew observable between sequential I/O elements. Significantly less clock-tree skew exists for I/O registers that are close to each other and fed by the same or adjacent clock-tree branches. Use the Xilinx FPGA_Editor and Timing Analyzer tools to evaluate clock skew specific to your application.

Table 73: Sample Window

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
T_{SAMP}	Sampling Error at Receiver Pins ⁽¹⁾	All	510	560	610	670	ps
T_{SAMP_BUFIO}	Sampling Error at Receiver Pins using BUFIO ⁽²⁾	All	300	350	400	440	ps

Notes:

1. This parameter indicates the total sampling error of Virtex-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include:
 - CLK0 MMCM jitter
 - MMCM accuracy (phase offset)
 - MMCM phase shift resolution
These measurements do not include package or clock tree skew.
2. This parameter indicates the total sampling error of Virtex-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFIO clock network and IODELAY to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

Table 74: Pin-to-Pin Setup/Hold and Clock-to-Out

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIO						
T _{PSCS} /T _{PHCS}	Setup/Hold of I/O clock	−0.28/1.09	−0.28/1.16	−0.28/1.33	−0.18/1.79	ns
Pin-to-Pin Clock-to-Out Using BUFIO						
T _{ICKOFC}	Clock-to-Out of I/O clock	4.22	4.59	5.22	5.63	ns

Revision History

The following table shows the revision history for this document:

Date	Version	Description of Revisions
06/24/09	1.0	Initial Xilinx release.
07/16/09	1.1	Revised the maximum V_{CCAUX} and V_{IN} numbers in Table 2, page 2. Removed empty column from Table 3, page 3. Revised specifications on Table 20, page 13. Updated Table 38, page 22 and added notes 1 and 2. Revised T_{DLYCCO_RDY} , $T_{IDELAYCTRL_RPW}$, and $T_{IDELAYPAT_JIT}$ in Table 53, page 41. Updated Table 58, page 46 to more closely match the DSP48E1 speed specifications. Updated T_{TAPTCK}/T_{TCKTAP} in Table 59, page 49. Updated XC6VLX130T parameters in Table 68 through Table 70, page 59.
08/19/09	1.2	Added values for -1L voltages and speed grade in all pertinent tables. Added V_{FS} and notes to Table 1 and Table 2. Removed DV_{PPIN} from the example in Figure 2. Added networking applications to Table 41, page 25. Changed and added to the block RAM F_{MAX} section in Table 57, page 44 including removing Note 12. Changed F_{PFDMAX} values and corrected units for $T_{STATPHAOFFSET}$ and $T_{OUTDUTY}$ in Table 64, page 52. Updated Table 71, page 60.
09/16/09	2.0	Added Virtex-6 HXT devices to entire document including GTH Transceiver Specifications. Updated speed specifications as described in Switching Characteristics, includes changes in Table 51, Table 57, Table 58, and Table 66 through Table 70. Comprehensive changes to Table 14, Table 15, and Table 16. Added conditions to DV_{PPOUT} and revised description of T_{OSKEW} in Table 17. Removed V_{ISE} specification and note from Table 18. Added note 3 to Table 23. Updated note 3 in Table 24. Updated LVCMOS25 delays in Table 44. Updated specification for T_{IOTPHZ} in Table 46. Removed $T_{BUFHSKEW}$ from Table 71, page 60 and added values for $T_{BUFIOSKEW}$. Added values in Table 74.

Date	Version	Description of Revisions
02/08/11	2.12	Removed note 1 from Table 4 as the larger devices (XC6VLX550T, XC6VLX760, XC6VSX475T, and XC6VHX565T) are now offered in -2I. Updated Table 4 and Table 5 with data for the XC6VHX380T in the FF(G)1154 package. In Table 41 , updated -1L specification for DDR3. Added Note 1 to Table 42 . Moved the XC6VHX380T devices in the FF(G)1154 package to production release in Table 43 using ISE 12.4 software with current speed specifications. Updated description for F_{INDUTY} in Table 64 .
02/25/11	3.0	Designated the data sheet as Preliminary for all devices not already labeled production in Table 42 . Changed the XC6VHX380T devices in all packages to production status in Table 42 and Table 43 . Removed note 1 from Table 42 . Added maximum specifications to Table 25 . Updated $T_{HAVCC2HAVCCRX}$ in Table 27 . Updated the typical values and notes in Table 28 and Table 29 . Added values to Table 30 and Table 31 . In Table 34 , added values for T_{LOCK} and T_{PHASE} . Updated the values in Table 36 and added note 3. Updated Table 37 and added note 4.
03/21/11	3.1	Updated Table 2 including Note 7 . In Table 4 , added Note 3 and -2E, extended temperature range to the XC6VLX550T, XC6VLX760, XC6VSX475T, and XC6VHX380T devices, and added Note 5 for the XC6VHX565T. Updated Table 28 typical values. Updated the description for $F_{IDELAYCTRL_REF}$ in Table 53 . Updated F_{MCCK} in Table 59 .
04/01/11	3.2	Added T_j values for C, E, and I temperature ranges to Table 2 . Updated the I_{CCQ} values in Table 4 . Updated F_{GCLK} in Table 34 . Designated the data sheet as Production for all devices not already labeled production in Table 42 . Changed the XC6VHX255T and XC6VHX565T devices in all packages to production status in Table 42 and Table 43 . This included updates to the Virtex-6 Device Pin-to-Pin Output Parameter Guidelines and Virtex-6 Device Pin-to-Pin Input Parameter Guidelines for these devices. Production speed specifications for these devices are available using the speed specification v1.14 in the ISE 13.1 software update. Updated and added package skew values to Table 72 ; these values are correct with regards to previous production released speed specifications in software. Updated copyright page 1 and Notice of Disclaimer .
12/08/11	3.3	Production release of the Defense-grade XQ devices in Table 42 and Table 43 using ISE v13.3 v1.17 Patch for -2 and -1 speed specifications; and v1.10 for -1L speed specifications. Added the XQ6VLX130T, XQ6VLX240T, XQ6VLX550T, XQ6VSX315T, and XQ6VSX475T to the data sheet which included adding Table 45 . Updated T_j in Table 2 . In Table 40 , updated T_j for most specifications and added Note 4 . Added Note 4 to Table 41 . Added -1(XQ) speed specification columns only to Table 50 , Table 51 , Table 52 , and Table 58 . Updated V_{OD} in Table 8 , V_{OCM} in Table 9 , and V_{OCM} and V_{DIFF} in Table 10 . Updated the Power-On Power Supply Requirements section. In Table 27 , updated maximum specification for $T_{HAVCC2HAVCCRX}$ and added Note 3 . Updated T_j in Table 40 . In Table 41 , increased the DDR LVDS receiver (SPI-4.2) -1 speed grade performance value from 1.0 Gb/s to 1.1 Gb/s. In Table 60 , updated the F_{MAX} to add a separate row for the LX760 device values. The speed specifications in the software tools have always matched these values for the LX760, the data sheet is now correct. Updated the notes for $T_{OUTJITTER}$ in Table 64 .
01/12/12	3.4	Added the temperature range -2E to Note 5 in Table 4 .

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